ыннони	T o				
м н о ^н о о и ч ч ч ч о	0	0	0	0	0
OOEEOCTA					
e Stamp ⊳	9/26 14:45	9/26 14:46	9/26 14:48	9/26 14:55	9/26 15:05
Тіле	2002/09/26	2002/09/26	2002/09/26	2002/09/26	2002/09/26
DBs	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB				
Search Text	Abe-katsuaki.in.	Abe-katsuaki.in. and electron adj microscope	250/311	250/311 and field adj of adj view	250/311 and image adj location
Hits	89	2	3129	0	8
Туре	BRS	BRS	BRS	BRS	BRS
· · · · · · · · · · · · · · · · · · ·	⊣	7	ю	4	2

Бинони	. 0	0	0	0	0
買ませるよりのままれませる				İ	
O O E E O C + N		<u>.</u>			
Time Stamp △	2002/09/26 15:06	2002/09/26 15:07	2002/09/26 15:07	2002/09/26 15:13	2002/09/26 15:13
	20	20	20	20	20(
DBs	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB				
Search Text	hitachi.as.	hitachi.as. and "field of view"	hitachi.as. and "field-of-view"	250/311 and "GUI"	250/311 and "field-of-view"
Hits	719149	0	16	4	11
Туре	BRS	BRS	BRS	BRS	BRS
	9	7	œ	ത	10

ынони	0	0	0	0	0		
因とよってのようはよりよっ							
OOEEOCHO							
Stamp △	15:28	15:29	15:31	15:32	15:33		
Time St	2002/09/26	2002/09/26	2002/09/26 2002/09/26 2002/09/26 2002/09/26				
DBs	B; O;		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB; IBM_TDB	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB		
Search Text	. and field adj of adj	(hitachi.as. and fault adj location) and electron adj microscope	(hitachi.as. and fault adj location) and display	(hitachi.as. and fault adj location) and coordinate	hitachi.as. and fault adj location		
Hits	0	0	24	9	114		
Туре	BRS	BRS	BRS	BRS	BRS		
	11	12	13	14	15		

ыннони	0	0	0	0	0
因とよった日 合きよれよせる					İ
O O E E O C + O			! ! !	! ! ! !	
Stamp ⊳	15:35	15:36	15:36	15:37	15:38
Time St	2002/09/26	2002/09/26	2002/09/26	2002/09/26	2002/09/26
m					
DBs	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
Search Text	hitachi.as. and defect adj location	scanning adj electron adj microscope	(scanning adj electron adj microscope) and wafer	((scanning adj electron adj microscope) and wafer) and defect adj location	(((scanning adj electron adj microscope) and wafer) and defect adj location) and coordinate
Hits	14	17277	3508	57	34
Туре	BRS	BRS	BRS	BRS	BRS
	16	17	18	19	20

ынони	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
ы ктой О Фич ц ч т ч о			<u> </u>		<u> </u>		<u> </u>		1				<u> </u>	<u> </u>			<u> </u>		<u> </u>	
OOEEOCHO	ļ	ļ	ļ	ļ	ļ	ļ	<u> </u>	ļ	ļ	ļ	<u> </u>	<u> </u>	ļ	<u> </u>	<u> </u>	ļ	ļ		ļ	
Stamp ⊳	7:	07:30	07:30	07:31	07:32	07:46	08:38	08:44	08:45	.5	3:	3:5	2	15:27	••	••	••		15:31	15:31
Time St	/60/	2002/09/27	/60/	2002/09/27	72/09/27	2002/09/27	2002/09/27	2002/09/27	2002/09/27	2/09/2	/09/2	2/09/2	2002/09/27	760/7	/60/3	2002/09/27	/60/7	2/09/2	2002/09/27	2002/09/27
DBs		USPAT	***************************************		USPAT						USPAT						USPAT		USPAT	USPAT
	6072178".P	386.	5568400".P	813545".PN.	3813545" "5568400" 072178").PN.		joel.as.	Inokuchi-masayuchi.in.	-ma	JRP	6259960.PN.	5863682.pn.	6259960.pn.	10	\mathbb{C}	7		00	0" and defect adj l	("700" and defect adj location) and field adj of adj view
Hits	-1	0		-	m	æ	48	0	Т	2	1			1805	⊣!	253	<u>ج</u>		44	0
Туре	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS	BRS
	21	22	23	24	25	26	27	28	29	30	31	32	33	34	35	36	37	38	39	40

ынони	0	0	0
В т н о ^н о о н н в ч н о и о н н в и и о и о и и и и и о и о и и и и и и		ļ	
០០ដដ្ឋាដ្ឋ ។ ១	-	<u> </u>	ļ
⊘ Ciu	15:32	15:32	15:32
Time Stamp △	2002/09/27 15:32	2002/09/27	2002/09/27
	20	20	20
DBs	USPAT	USPAT	USPAT
Search Text	("700" and defect adj location) and "SEM"	438/200	438/200 and defect adj location
Type Hits	8	413	0
Туре	BRS	BRS 413	BRS
	41	42	43